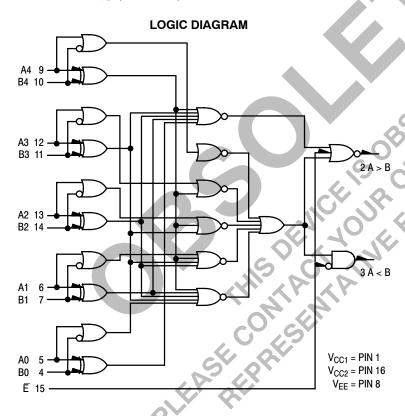
5-Bit Magnitude Comparator

The MC10166 is a high speed expandable 5-bit comparator for comparing the magnitude of two binary words. Two outputs are provided: A < B and A > B. A = B can be obtained by NORing the two outputs with an additional gate. A high level on the enable function forces both outputs low. Multiple MC10166s may be used for larger word comparisons.

- $P_D = 440 \text{ mW typ/pkg (No Load)}$
- t_{pd} =Data to Output 6.0 ns typ
- E to output 2.5 ns typ
- t_r , $t_f = 2.0$ ns typ (20%–80%)



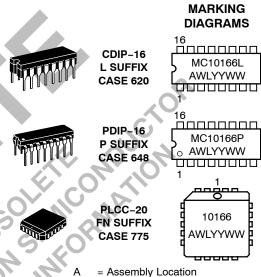
TRUTH TABLE

	Inputs	Outputs		
Ē	Α	В	A < B	A > B
Н	Х	Х	L	L
L	Word A =	Word B	L	L
L	Word A >	Word B	L	Н
L	Word A <	Word B	Н	L



ON Semiconductor

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DIP PIN ASSIGNMENT

WL = Wafer Lot YY = Year

WW = Work Week

	1		~ ~		1	
V_{CC1}		1		16		V_{CC2}
A>B		2		15		Ē
A <b< td=""><td></td><td>3</td><td></td><td>14</td><td></td><td>B2</td></b<>		3		14		B2
В0		4		13		A2
A0		5		12		A3
A1		6		11		В3
B1		7		10		B4
V_{EE}		8		9		A4
					•	

Pin assignment is for Dual-in-Line Package. For PLCC pin assignment, see the Pin Conversion Tables on page 18 of the ON Semiconductor MECL Data Book (DL122/D).

ORDERING INFORMATION

Device	Package	Shipping
MC10166L	CDIP-16	25 Units / Rail
MC10166P	PDIP-16	25 Units / Rail
MC10166FN	PLCC-20	46 Units / Rail

ELECTRICAL CHARACTERISTICS

		Test Limits								
		Pin Under	-30)°C	+25°C			+85	5°C	
Characteristic	Symbol	Test	Min	Max	Min	Тур	Max	Min	Max	Unit
Power Supply Drain Current	ΙE	8		117		85	106		117	mAdd
Input Current	I _{inH}	5		350			220		220	μAdd
	I _{inL}	5	0.5		0.5			0.3		μAdd
Output Voltage Logic 1	V _{OH}	2 3	-1.060 -1.060	-0.890 -0.890	-0.960 -0.960		-0.810 -0.810	-0.890 -0.890	-0.700 -0.700	Vdc
Output Voltage Logic 0	V_{OL}	2	-1.890 -1.890	-1.675 -1.675	-1.850 -1.850		-1.650 -1.650	-1.825 -1.825	-1.615 -1.615	Vdc
Threshold Voltage Logic 1	V _{OHA}	2 3	-1.080 -1.080		-0.980 -0.980			-0.910 -0.910		Vdc
Threshold Voltage Logic 0	V _{OLA}	2 3		-1.655 -1.655			-1.630 -1.630		-1.595 -1.595	Vdc
Switching Times (50Ω Load)								.0		ns
Propagation Data to Output	t ₉₊₂₊	2	1.0	8.0	1.0	6.0	7.6	1.0	8.4	
Delay	t ₉₋₂₋	2	1.0	8.0	1.0	6.0	7.6	1.0	8.4	
	t ₁₁₋₂₊ t ₁₁₊₂₋	2 2	1.0 1.0	8.0 8.0	1.0 1.0	6.0 6.0	7.6 7.6	1.0 1.0	8.4 8.4	
	t ₇₊₃₊	3	1.0	8.0	1.0	6.0	7.6	1.0	8.4	
	t- 0	3	1.0	8.0	1.0	6.0	7.6	1.0	8.4	
Enable to Output	t ₁₅₋₃₊ t ₁₅₊₃₋	3	1.0 1.0	3.8 3.8	1.0 1.0	2.5 2.5	3.6 3.6	1.0 1.0	4.0 4.0	
Rise Time (20 to 80%)	t ₂₊	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	
Fall Time (20 to 80%)	t ₂₋	2	1.0	3.6	1.1	2.0	3.5	1.1	3.8	
,	t ₂₊ t ₂₋	2 2	1.0	3.6	1.1	2.0 2.0	3 .5			

ELECTRICAL CHARACTERISTICS (continued)

			TEST VOLTAGE VALUES (Volts)					
	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}			
	-0.890	-1.890	-1.205	-1.500	-5.2			
	-0.810	-1.850	-1.105	-1.475	-5.2			
	-0.700	-1.825	-1.035	-1.440	-5.2			
	TEST V	OLTAGE APP	LIED TO PIN	IS LISTED B	ELOW			
Characteristic	Symbol	Under Test	V _{IHmax}	V _{ILmin}	V _{IHAmin}	V _{ILAmax}	V _{EE}	(V _{CC}) Gnd
Power Supply Drain Current	ΙE	8		4,7,10,11,14			8	1, 16
Input Current	I _{inH}	5	5				8	1, 16
	I _{inL}	5		5			8	1, 16
Output Voltage Logic 1	V _{OH}	2	5				8	1, 16
		3	4				8	1, 16
Output Voltage Logic 0	V _{OL}	2 3	5, 15 4, 15				8	1, 16 1, 16
Threshold Voltage Logic 1	V _{OHA}	2 3	5 4			15 15	8 8	1, 16 1, 16
Threshold Voltage Logic 0	V _{OLA}	2 3	5 4		15 15	700	8 8	1, 16 1, 16
Switching Times (50Ω Load)			+1.11V		Pulse In	Pulse Out	-3.2 V	+2.0
Propagation Delay Data to Output	t ₉₊₂₊ t ₉₋₂₋ t ₁₁₋₂₊ t ₁₁₊₂₋ t ₇₊₃₊ t ₇₋₃₋	2 2 2 2 2 3 3	12 12 6 6	5 OF S	9 9 11 11 7 7	2 2 2 2 2 3 3	8 8 8 8	1, 16 1, 16 1, 16 1, 16 1, 16 1, 16
Enable to Output	t ₁₅₋₃₊ t ₁₅₊₃₋	3 3	10 10	UP LO	15 15	3 3	8 8	1, 16 1, 16
Rise Time (20 to 80%)	t ₂₊	2	7, 'C), (9	2	8	1, 16
Fall Time (20 to 80%)	t ₂₋	2	1		9	2	8	1, 16

Each MECL 10,000 series circuit has been designed to meet the dc specifications shown in the test table, after thermal equilibrium has been established. The circuit is in a test socket or mounted on a printed circuit board and transverse air flow greater than 500 linear fpm is maintained. Outputs are terminated through a 50-ohm resistor to -2.0 volts. Test procedures are shown for only one gate. The other gates are tested in the same manner.

APPLICATION INFORMATION

FIGURE 1 — 9-BIT MAGNITUDE **COMPARATOR**

B2

ВЗ

A < B

A<B

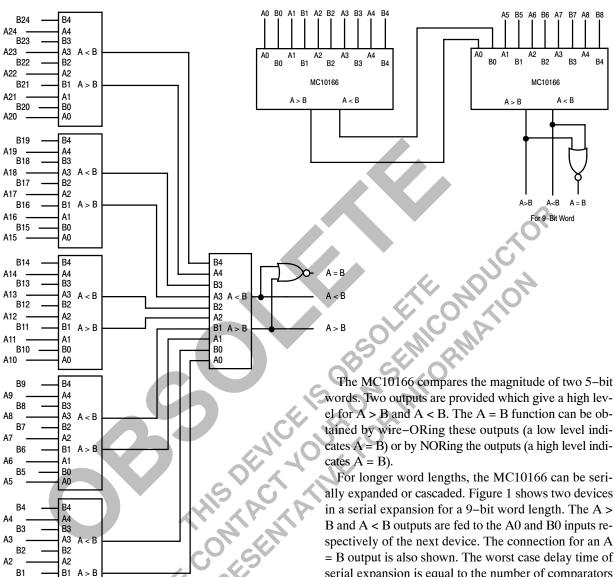


FIGURE 2 — 25-BIT MAGNITUDE COMPARATOR

A1

A0

B0

A1

B0

A0

words. Two outputs are provided which give a high level for A > B and A < B. The A = B function can be obtained by wire-ORing these outputs (a low level indicates A = B) or by NORing the outputs (a high level indi-

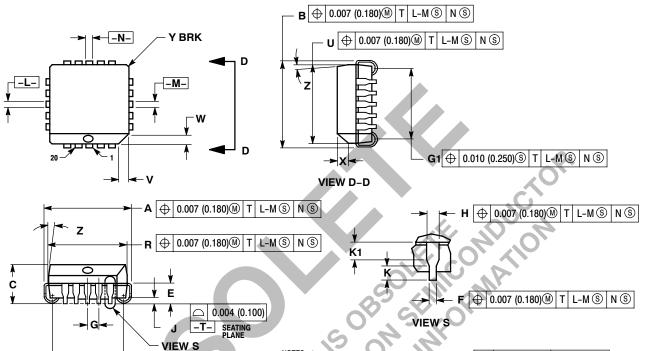
ally expanded or cascaded. Figure 1 shows two devices in a serial expansion for a 9-bit word length. The A > B and A < B outputs are fed to the A0 and B0 inputs respectively of the next device. The connection for an A = B output is also shown. The worst case delay time of serial expansion is equal to the number of comparators times the data-to-output delay.

For shorter delay times than possible with serial expansion, devices can be cascaded. Figure 2 shows a 25-bit cascaded comparator whose worst case delay is two data-to-output delays. The cascaded scheme can be extended to longer word lengths.

PACKAGE DIMENSIONS

PLCC-20 **FN SUFFIX**

PLASTIC PLCC PACKAGE CASE 775-02 **ISSUE C**



NOTES:

G1 0.010 (0.250) T L-M N N

- IOTES:

 1. DATUMS -L-, -M-, AND -N- DETERMINED
 WHERE TOP OF LEAD SHOULDER EXITS PLASTIC
 BODY AT MOLD PARTING LINE.

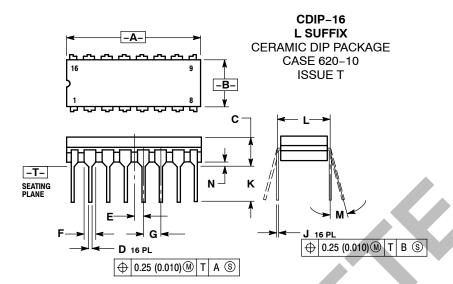
 2. DIMENSION 61, TRUE POSITION TO BE
 MEASURED AT DATUM -T-, SEATING PLANE.

 3. DIMENSIONS R AND U DO NOT INCLUDE MOLD
 FLASH: ALLOWABLE MOLD FLASH IS 0.010 (0.250)
 DED SIGN PER SIDE.
 DIMENSIONING AND TOLERANCING PER ANSI

- 714.5M, 1982.
 5. CONTROLLING DIMENSION: INCH.
 6. THE PACKAGE TOP MAY BE SMALLER THAN THE PACKAGE BOTTOM BY UP TO .0.12 (0.300). DIMENSIONS R AND U ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY EXCLUSIVE OF MOLD FLASH, TIE BAR BURRS, GATE BURRS AND INTERLEAD FLASH, BUT INCLUDING ANY MISMATCH BETWEEN THE TOP
- AND BOTTOM OF THE PLASTIC BODY.
 DIMENSION H DOES NOT INCLUDE DAMBAR PROTRUSION OR INTRUSION. THE DAMBAR PROTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE GREATER THAN 0.037 (0.940). THE DAMBAR INTRUSION(S) SHALL NOT CAUSE THE H DIMENSION TO BE SMALLER THAN 0.025 (0.635).

	INC	HES	MILLIM	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.385	0.395	9.78	10.03
В	0.385	0.395	9.78	10.03
С	0.165	0.180	4.20	4.57
Ε	0.090	0.110	2.29	2.79
F	0.013	0.019	0.33	0.48
G	0.050	BSC	1.27	BSC
Н	0.026	0.032	0.66	0.81
J	0.020		0.51	
K	0.025		0.64	
R	0.350	0.356	8.89	9.04
U	0.350	0.356	8.89	9.04
٧	0.042	0.048	1.07	1.21
W	0.042	0.048	1.07	1.21
Х	0.042	0.056	1.07	1.42
Υ		0.020		0.50
Z	2°	10°	2 °	10 °
G1	0.310	0.330	7.88	8.38
K1	0.040		1.02	

PACKAGE DIMENSIONS

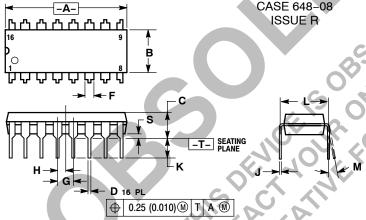


NOTES:

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
- CONTROLLING DIMENSION: INCH.
 DIMENSION L TO CENTER OF LEAD WHEN FORMED PARALLEL.
- DIMENSION F MAY NARROW TO 0.76 (0.030) WHERE THE LEAD ENTERS THE CERAMIC

	INC	HES	MILLIN	ETERS			
DIM	MIN	MAX	MIN	MAX			
Α	0.750	0.785	19.05	19.93			
В	0.240	0.295	6.10	7.49			
C		0.200		5.08			
D	0.015	0.020	0.39	0.50			
Е	0.050	BSC	1.27 BSC				
F	0.055	0.065	1.40	1.65			
G	0.100	BSC	2.54 BSC				
H	0.008	0.015	0.21	0.38			
K	0.125	0.170	3.18	4.31			
L	0.300	BSC	7.62	BSC			
M	0°	15°	0°	15°			
N	0.020	0.040	0.51	1.01			





NOTES

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982. CONTROLLING DIMENSION: INCH.
- DIMENSION L TO CENTER OF LEADS WHEN FORMED PARALLEL.
- DIMENSION B DOES NOT INCLUDE MOLD FLASH.
 ROUNDED CORNERS OPTIONAL.

	INC	HES	MILLIN	ETERS	
DIM	MIN	MAX	MIN	MAX	
PΑ	0.740	0.770	18.80	19.55	
В	0.250	0.270	6.35	6.85	
С	0.145	0.175	3.69	4.44	
D	0.015	0.021	0.39	0.53	
F	0.040	0.70	1.02	1.77	
G	0.100	BSC	2.54 BSC		
Н	0.050	BSC	1.27 BSC		
J	0.008	0.015	0.21	0.38	
K	0.110	0.130	2.80	3.30	
L	0.295	0.305	7.50	7.74	
M	0°	10°	0°	10 °	
S	0.020	0.040	0.51	1.01	

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